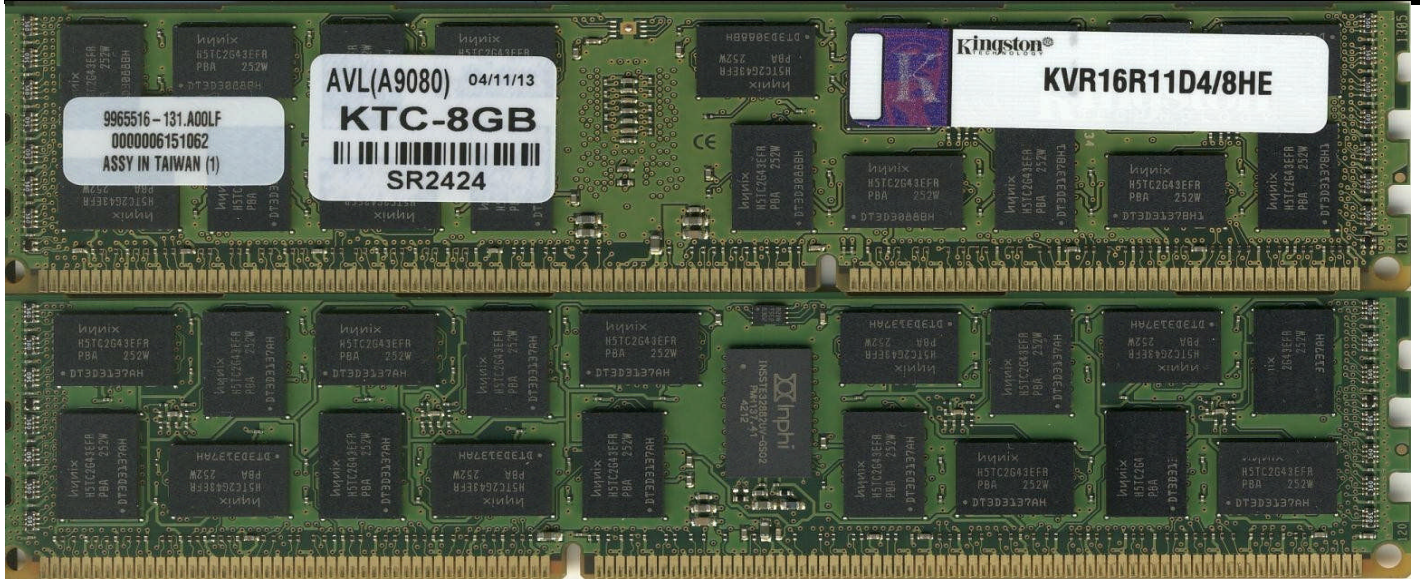
	AVL Supermicro server platform Memory Module Qualification Test		
	Intel X5650(WSM) x 2, Intel 5520 (Tylersburg), Rev C2	Test Results	Pass
	PN: KVR16R11D4/8HE (8GB / RDIMM / ECC) On: X8DT3 Rev.2.00		

RP77D3x-128-KI-SQ-SMC-V2		Module Information		Rev 04/25/2013
AVL WorkOrder #	WC6875	AVL A#	9080	
Start Date	6/3/2013	End Date	6/5/2013	
Tested By	Van N.			
Module Manufacturer	Kingston			
Module Part Number	KVR16R11D4/8HE			
Module BOM Number	9965516-131.A00LF			
Module Capacity / Memory Type / ECC	8GB / RDIMM / ECC			
Module Configuration (Width, # of devices, # of Ranks)	1Gx72 /36 Devices / 2 Ranks			
Module Speed (Data rate of Mbps, CL-tRP-tRCD)	DDR3-1600 /11-11-11			
DRAM Device Vendor	Hynix			
DRAM Device Part Number / Date code	H5TC2G43EFR-PBA	1252		
DRAM Die Revision / Process Technology (nm)	E			
DRAM Device Config (Density / Width)	512Mbit / x4 / 512Mx4bit			
Thermal Sensor Device Vendor / Part Number / Revision	STMicro			
Register Device Vendor / Part Number / Revision	Inphi	SSTE32882	2.1	



Platform System Information				
Motherboard Info (Model# & MB Revision & MB S/N & AVL S/N)	X8DT3	2.00	OM06S30241	SK4377
BISO Revision / BIOS Date / MRC Rev.	2.1b	10/28/2011		
CPU / Speed	Intel X5650(WSM) x 2		2.66GHz	
Chipset info (Stepping)	Intel 5520 (Tylersburg), Rev C2			



AVL Supermicro server platform Memory Module Qualification Test

Intel X5650(WSM) x 2, Intel 5520 (Tylersburg), Rev C2

PN: KVR16R11D4/8HE (8GB / RDIMM / ECC) On: X8DT3 Rev.2.00

Test Results:

PASS

Comments:

AVL Memory Module Qual Test Results Summary

Test # and name	Test Description	KVR16LR11D 4/8HE	Test	Comments
			Results	
1. Latest BIOS Upgrade & Configuration	Download / Upgrade latest BIOS & record size and speed detection	Per test platform, DIMM & config spec	Done	Record memory size & speed at each test only
2. SPD Check	Memory module SPD content check for JEDEC compliance	JEDEC	Pass	Use proprietary tools
3. Reset Cycle	Run Linux based diags & utility software @55°C	50 loops	Pass	1 DIMM Per Channel when applicable
4a. Stress Application Test	Run Linux based diags & utility software @55°C	8 Hour per config	Pass	DIMM Loading per spec
4b. Stream Benchmark Test		5 loop per config	Pass	DIMM Loading per spec
4b. Reset Cycle		200 loop per config	Pass	DIMM Loading per spec
5. Functional Stress Test	Memory Stress Test @55°C	12hrs	Pass	DIMM Loading per spec
6. Stress Application Test	Run Linux based diags & utility software @55°C	8hrs	N/A	3 DIMM Per Channel when applicable

Note: All test under IMC Vdd=Nom, Vref=Vddnom/2